

Characterization of a back-illuminated sCMOS camera for soft X-ray beamlines at Synchrotron SOLEIL

Kewin Desjardins, Benjamin Boitrelle, H. Popescu, P. Mercère, C. Meneglier, R. Gaudemer, S. Pautard, A. Noureddine and N. Jaouen

Synchrotron SOLEIL, L'Orme des Merisiers, Saint-Aubin, BP48, 91192, GIF-sur-YVETTE, France

sCMOS-BSI camera adapted in-vacuum for new experiment at SOLEIL

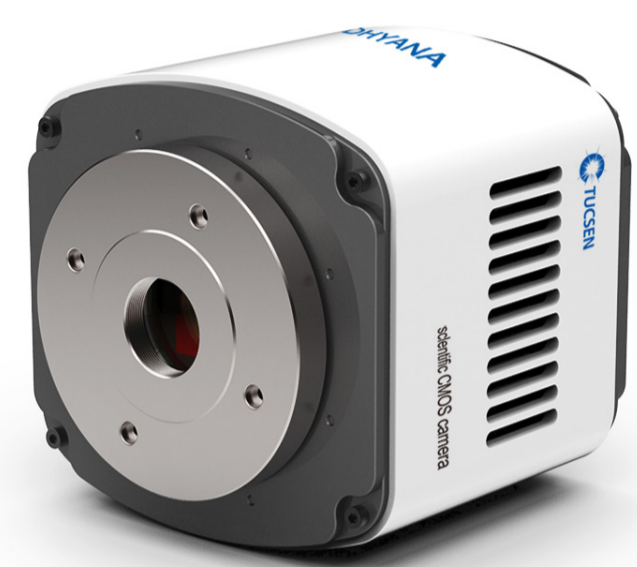
Scientific motivations

Soft X-ray applications using last generation of synchrotron facilities, such as coherent x-ray scattering experiments, require **large 2D direct sensor with small pixels, low noise and high frame rate**. Last generation of CMOS sensor used under visible light illumination made interesting progress in this direction. Recently, a new type of scientific CMOS Back Side Illuminated (sCMOS-BSI) has been proposed. We report on the characterization of this sCMOS-BSI using synchrotron beams between 40 and 2000 eV on the soft X-ray beamlines METROLOGIE (Bending Magnet) and SEXTANTS (Undulator) at SOLEIL synchrotron in France.

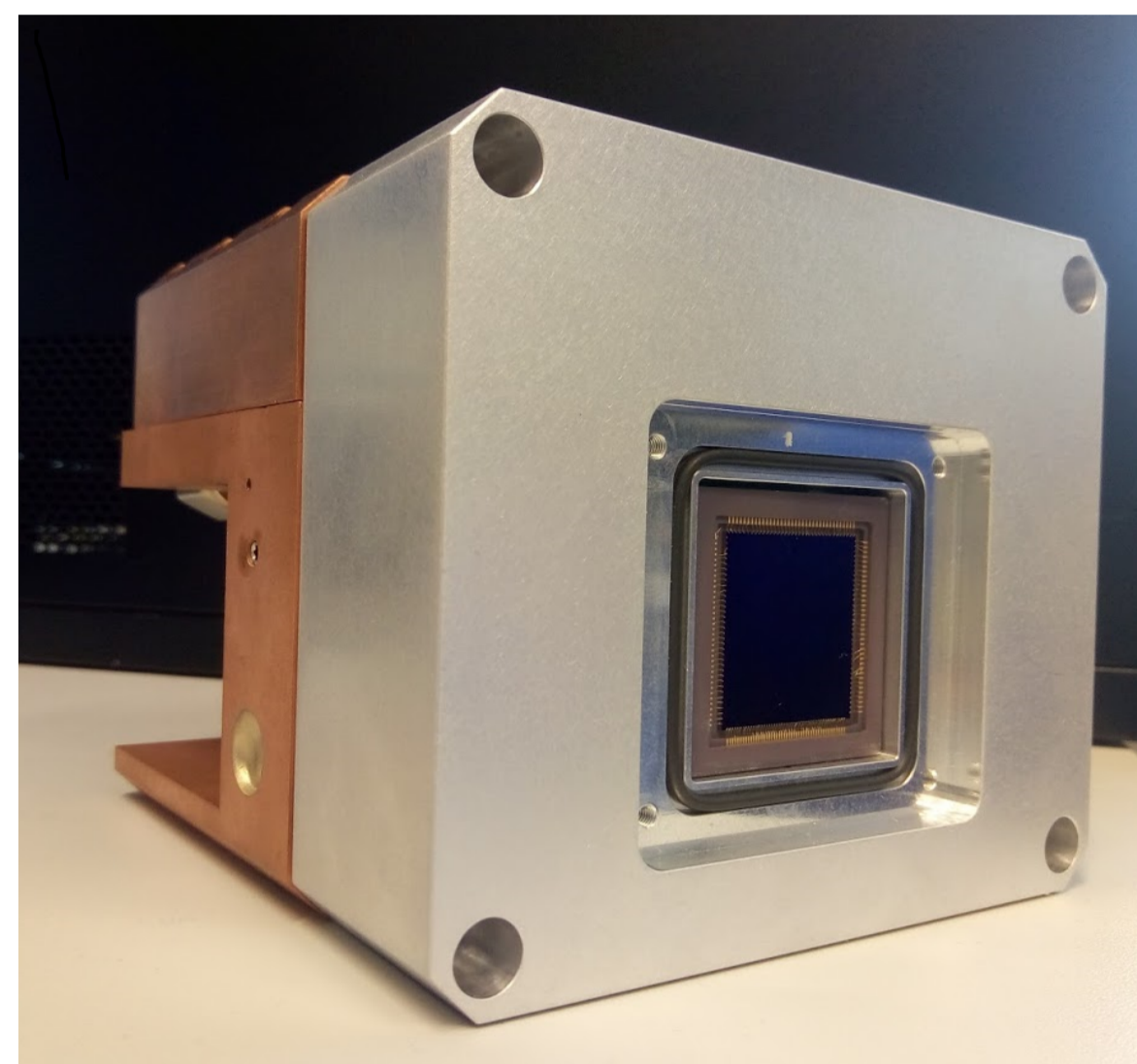
GSENSE400 sCMOS BSI sensor

Developed by Gpixel and integrated into the TUCSEN Dhyana95 camera
Acquisition mode:

- High gain
- Low gain
- HDR (High Dynamic Range): combination: combination of Low and High gain images



Adaptation for in-vacuum experiment designed and integrated by SOLEIL



GSENSE400-BSI Specification

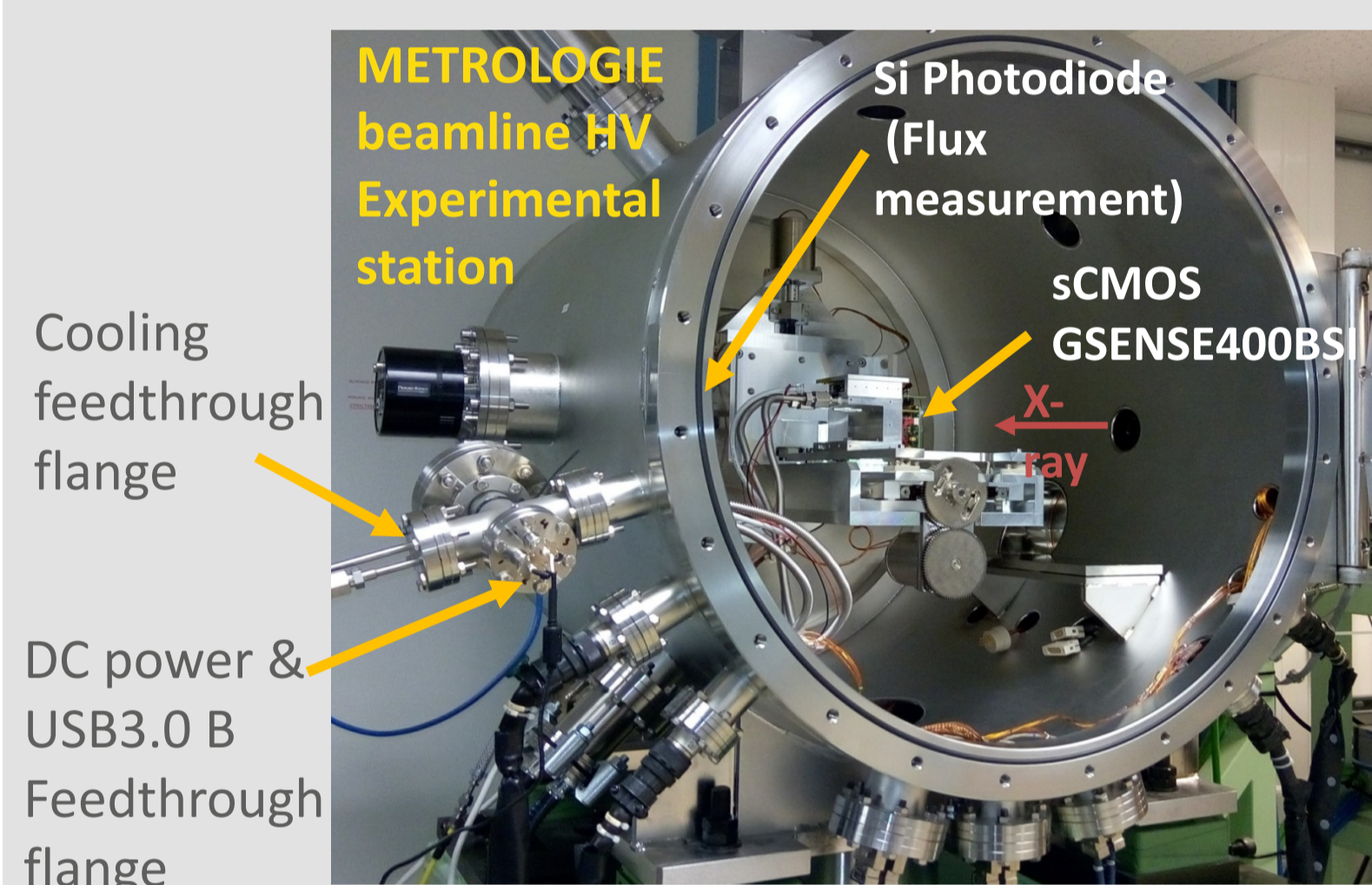
Resolution	2048 x 2048
Pixel size	11 μm x 11 μm
Sensitive area	22.5 mm x 22.5 mm
Shutter type	Rolling shutter
Dark noise	1.2 e ⁻
Dynamic range	> 97 dB
Full well charge	91 ke ⁻
Frame rate	48 fps @ STD, 24 fps @ HDR
Dark current	0.2 e ⁻ /s/pix @ -50°C

METROLOGIE beamline – UV Branch

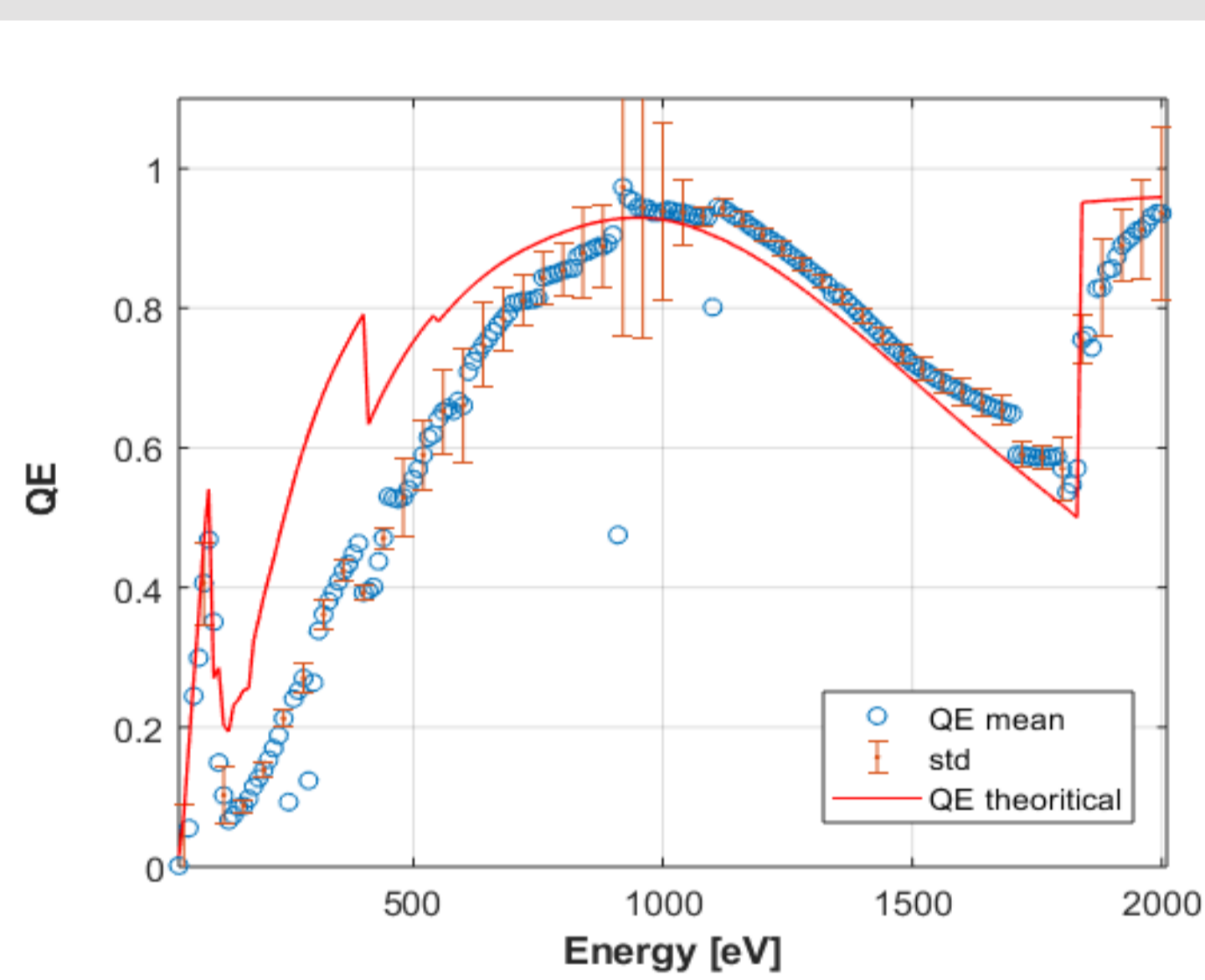
- Energy: 30 to 1900 eV
- Flux: few 10⁹ photons/s
- Beamsize: 200 (H) x 150 (V) μm^2 FWHM
- End-station: Two-axis high vacuum goniometer

Tests at METROLOGIE beamline

Quantum efficiency measurement

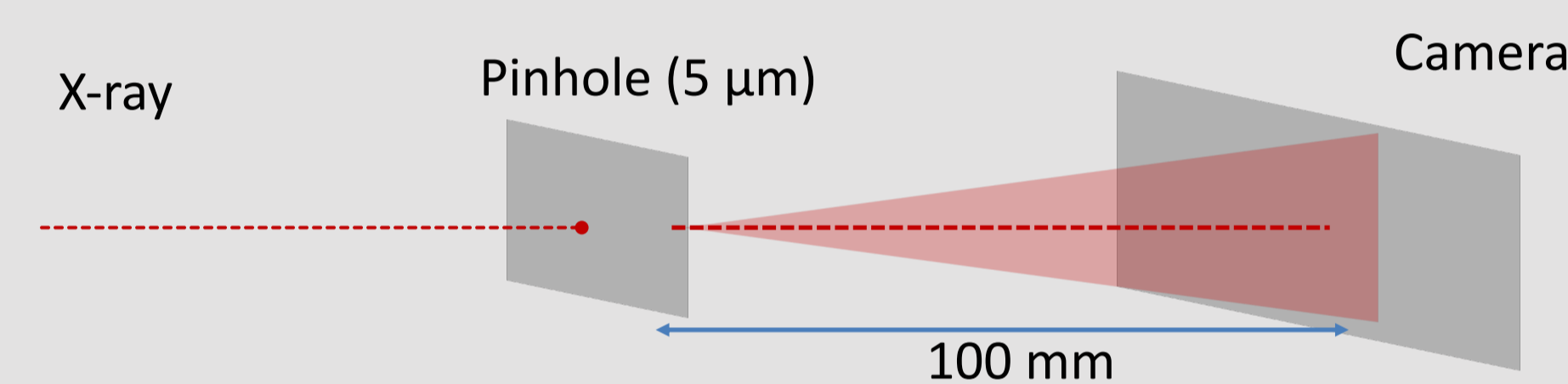


Quantum efficiency (Q.E.) measurement compared to simulated Q.E. with a sensor made of 7.5 nm of SiO₂, 63 nm of SiN and Si-Epi of 10 μm

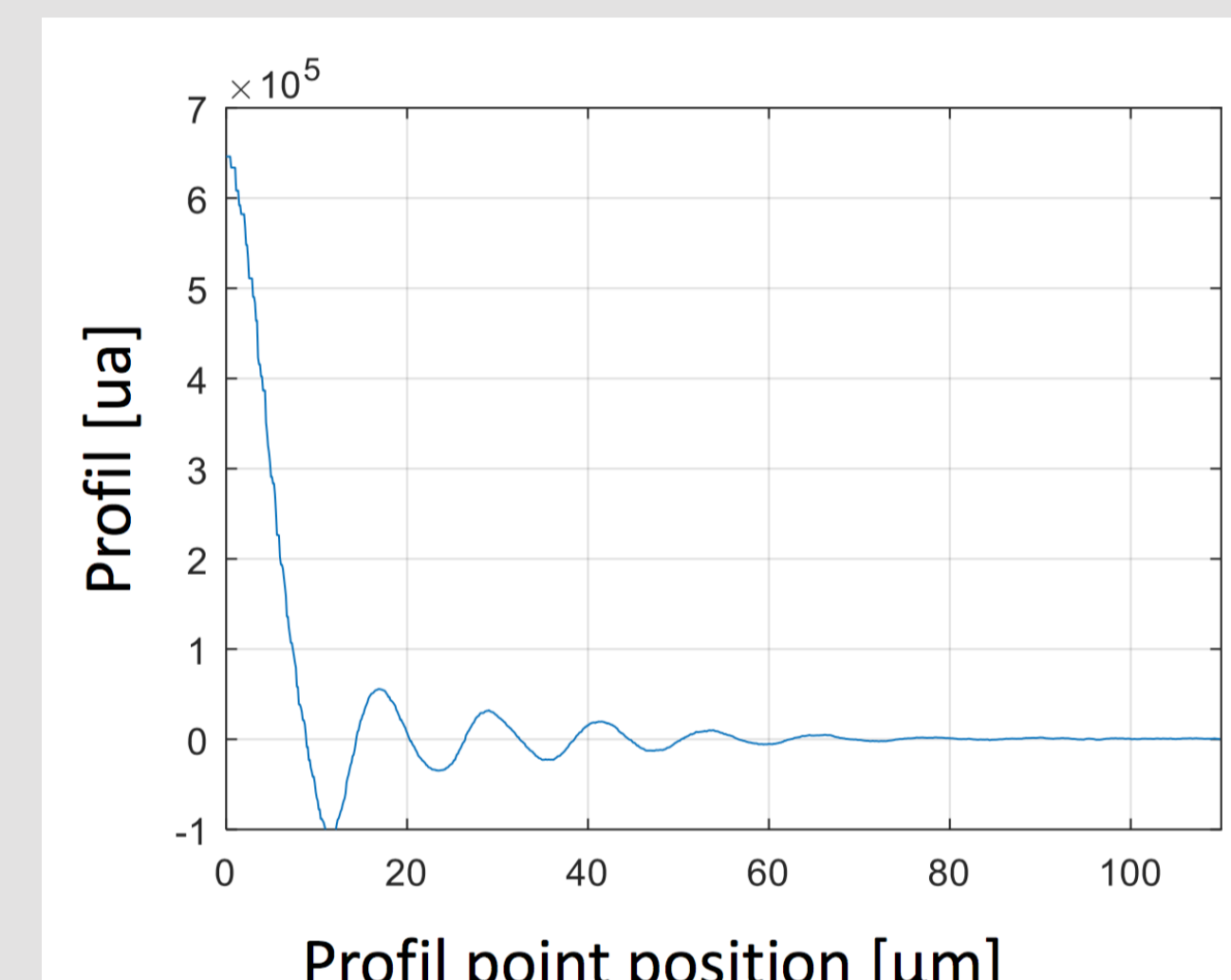
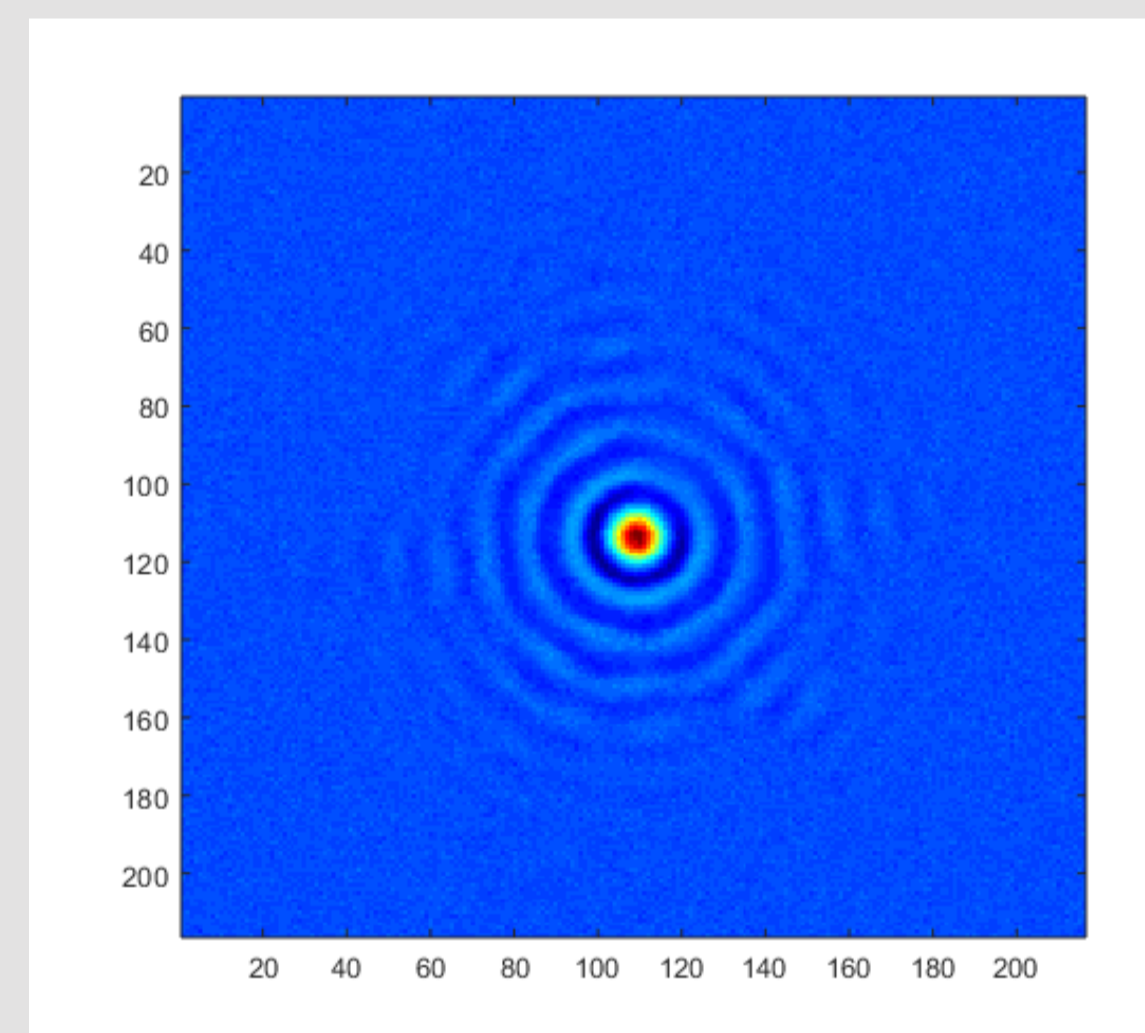


- @ 90 eV: transient rise efficiency coming from X-ray beam transmission through coated thin layer (SiO₂ and SiN)
- @ 410 eV: absorption from Nitrogen
- 550 eV: absorption from Oxygen
- 1830 eV: absorption from Silicon

Diffraction pattern of a pinhole with 186 eV beam



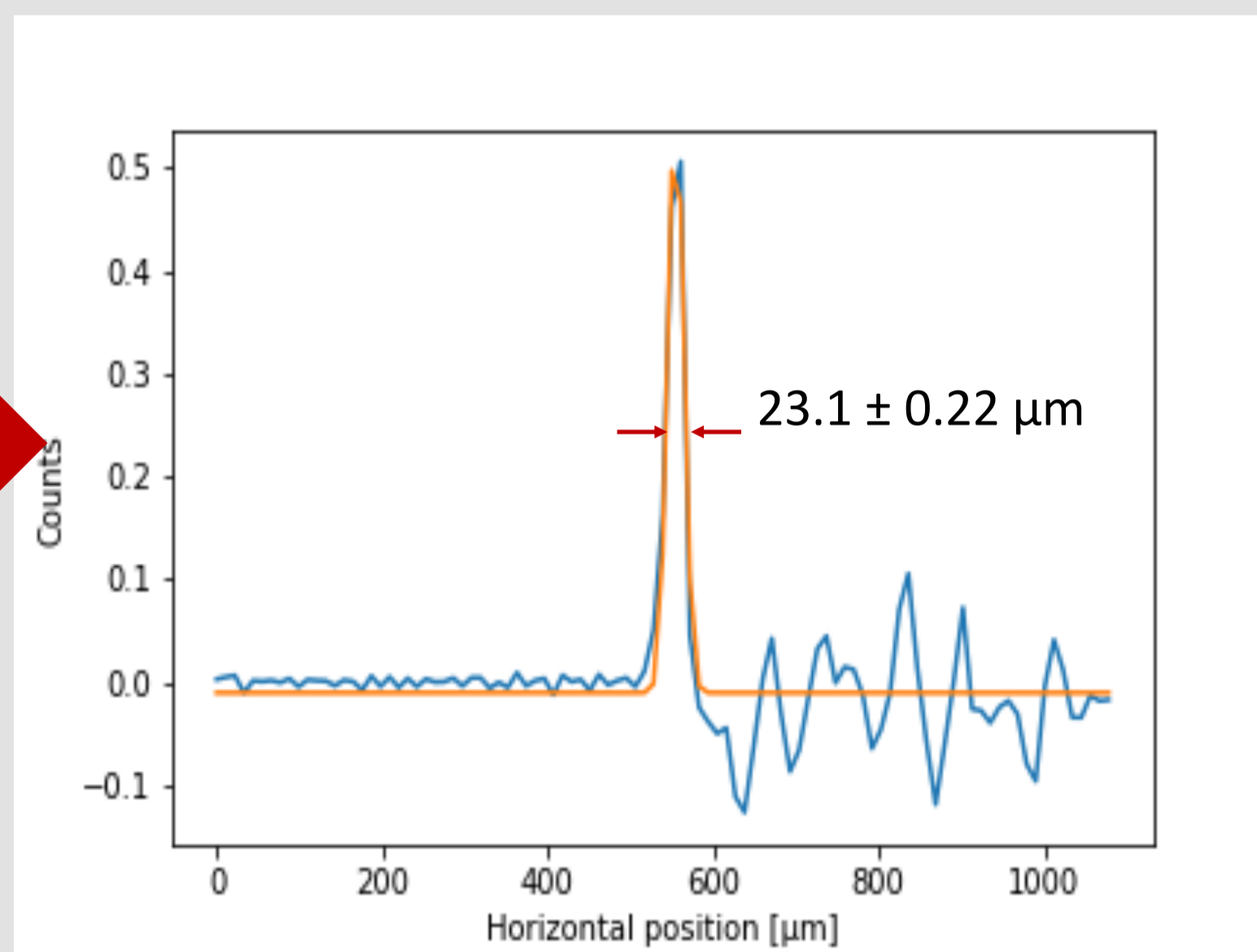
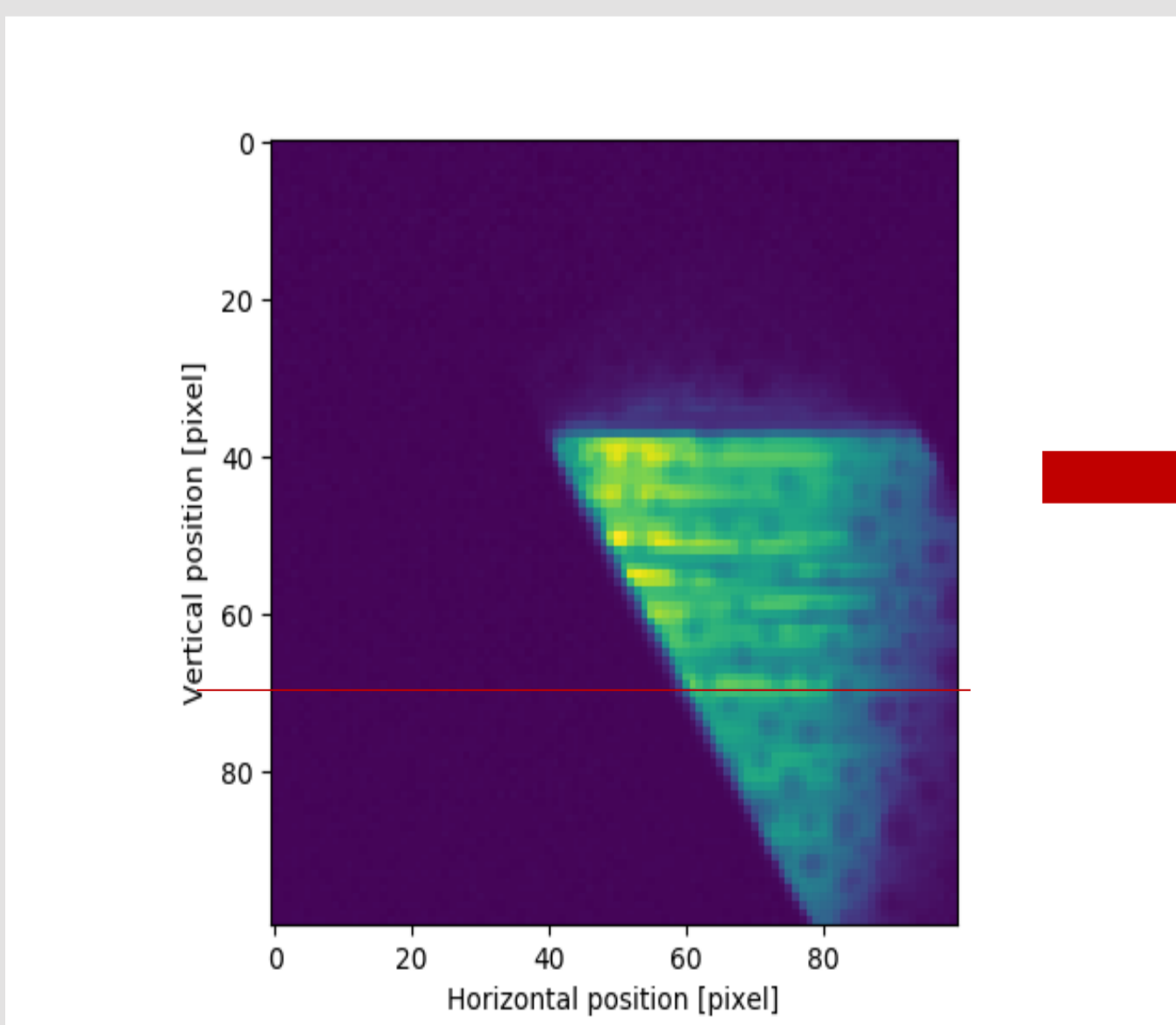
Sum of 100 dark corrected images (100 ms exposure time)



Airy disk presents a nice first result with this non-dedicated setup with the good camera dynamic able to visualize several orders of the diffraction pattern.

Signal spatial dispersion (slanted edge)

A Plexiglas with 3 holes is located as near as possible from the sensor. Two of these holes have a slit of Si₃N₄ with different orientations and one hole is free for setting the beam energy and size before acquiring data



Acquisition program

For improving analysis, different acquisitions have been done:

- accumulation of 100 images with beam and slit
- 100 dark images with slit
- 100 images with beam and without slit
- 100 dark images without slit

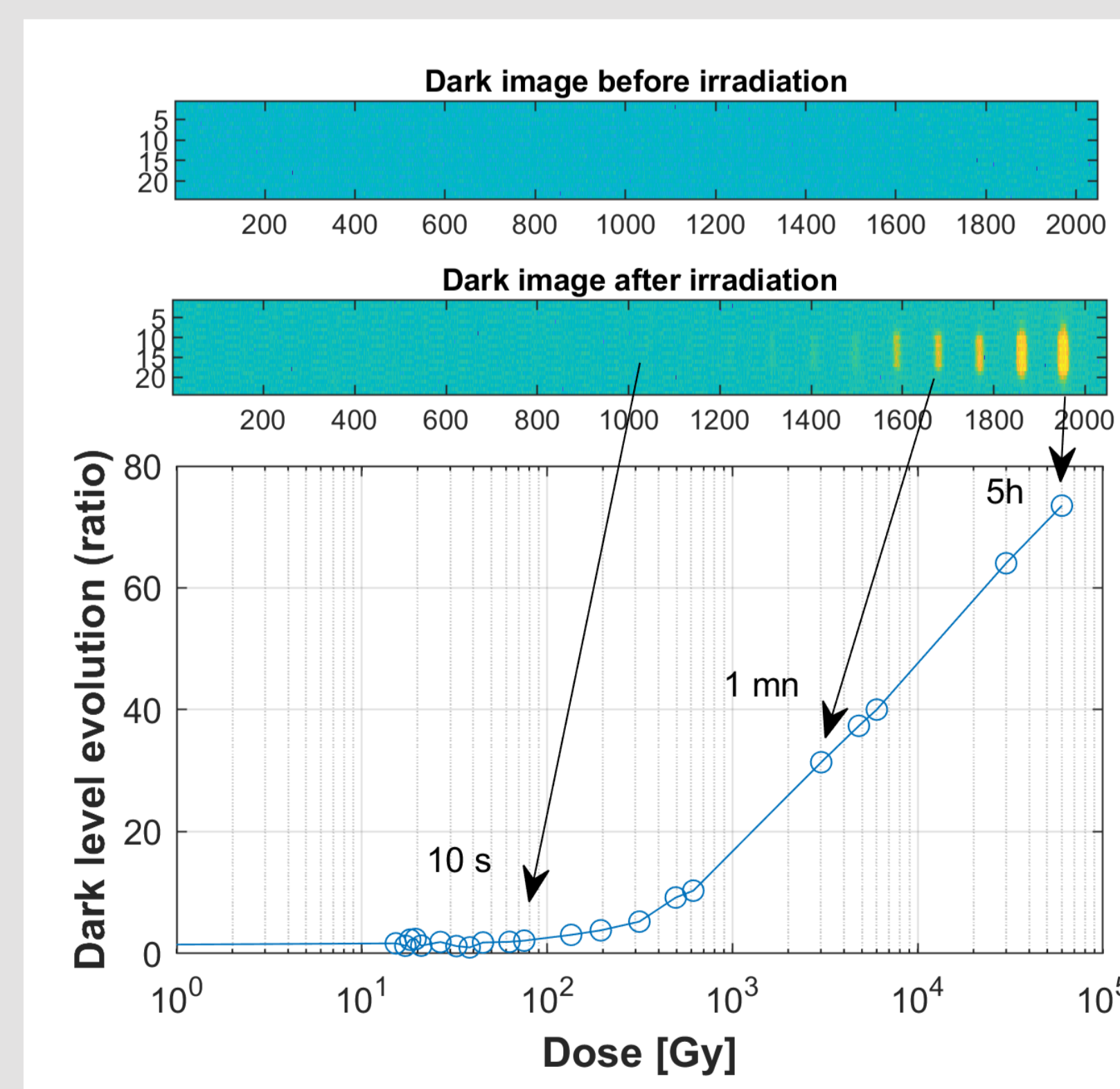
• Mechanics had some lubricant traces => a thin layer of oil has been accidentally deposited on the surface of the sensor while pumping

Results

- Temporal offset reduced and images normalised
- Profile gets for position where the edge does not have a "oil bubble"
- Calculate derivative of this profile and fit with a gaussian
- FWHM measured:

2.5 pixels \pm 0.02 => 23.1 \pm 0.22 μm @ 1050 eV

Radiation damage evaluation (E = 1600 eV, $\phi = 9 \cdot 10^6$ ph/s)



Comparison of dark image signal before and after irradiation:

- Different energies and fluxes have been chosen
- After ~ 50 Gy, there is a degradation on the dark level

Then, the incident photon flux should be limited especially for the high energy beam (>1000 eV) which penetrates the sensor deeply.

Summary and perspectives

- GSENSE400-BSI has been evaluated and adapted for in-vacuum tests
- Quantum Efficiency has been measured and fits reasonably to the simulation
- Diffraction images have been recorded and prove capability to use this camera for soft X-ray application
- Incident photon flux should be limited for energy below 1 keV to avoid damages
- Line Spread Function gives a spatial resolution of few pixels and this measure will be improved
- A camera will be installed in the new experimental station of the SEXTANTS beamline for user operation